

Notice of References Cited

Application/Control No.

10/529,517

Applicant(s)/Patent Under

Reexamination

IKEDA ET AL.

Examiner

HENOK G. HEYI

Art Unit

2627

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0003948 A1	01-2002	Himeno et al.	386/98
*	B US-6,393,196 B1	05-2002	Yamane et al.	386/52
*	C US-2004/0047589 A1	03-2004	Kim, Kwang Su	386/046
*	D US-2004/0052275 A1	03-2004	Murakami et al.	370/503
*	E US-6,778,760 B1	08-2004	Kagle, Jonathan C.	386/96
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.